

<b>Notice of References Cited</b>	Application/Control No. 09/975,963	Applicant(s)/Patent Under Reexamination CHO ET AL.	
	Examiner Long Pham	Art Unit 2814	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-US006300198B1	10-2001	Aeugle et al.	
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Long Pham  
4/18/09

<b>Notice of References Cited</b>	Application/Control No. 10/617,183	Applicant(s)/Patent Under Reexamination CHO ET AL.	
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